

Notice of References Cited	Application/Control No. 10/537,470	Applicant(s)/Patent Under Reexamination YANO ET AL.	
	Examiner Hieu P. Nguyen	Art Unit 2817	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,862,461	01-1999	Yoshizawa et al.	455/127.3
*	B	US-6,114,911	09-2000	Iwai et al.	330/295
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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